

ABSTRACT

Disclosed is a rubber socket apparatus for testing circuits of an electronic device, the apparatus having a shielding layer or a film that can remove signal noise.

The rubber socket apparatus for testing circuits of an electronic device, according to

5 one aspect of the present invention, may comprise: a plurality of test pins aligned so that circuits of an electronic device can be tested; a rubber layer in which the plurality of test pins are embedded upright; and a shielding film which is in close contact with either the upper surface or the lower surface of the rubber layer for shielding or signal noise reduction.

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FIG. 4